







**SN74HCS273** SCLS851B - MARCH 2021 - REVISED OCTOBER 2021

# SN74HCS273 Octal D-Type Flip-Flop with Schmitt-Trigger Inputs and Asynchronous Clear

## 1 Features

- Wide operating voltage range: 2 V to 6 V
- Schmitt-trigger inputs allow for slow or noisy input signals
- Low power consumption
  - Typical I<sub>CC</sub> of 100 nA
  - Typical input leakage current of ±100 nA
- ±7.8-mA output drive at 6 V
- Extended ambient temperature range: -40°C to +125°C, TA

## 2 Applications

- Synchronize data to clock
- Simple memory 8 bits

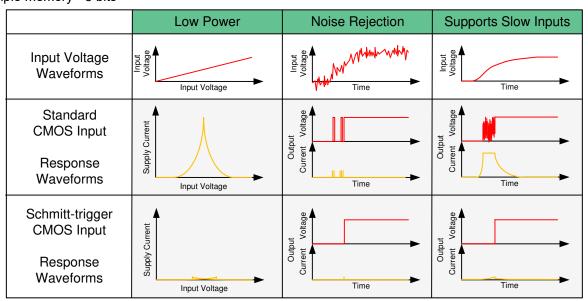
## 3 Description

The SN74HCS273 device are octal positive-edgetriggered D-type flip-flops with Schmitt-trigger inputs, shared direct active low clear (CLR) input and clock (CLK).

### **Device Information**

PART NUMBER	PACKAGE <sup>(1)</sup>	BODY SIZE (NOM)		
SN74HCS273PW	TSSOP (20)	6.50 mm × 4.40 mm		
SN74HCS273RKS	VQFN (20)	4.50 mm × 2.50 mm		

For all available packages, see the orderable addendum at the end of the data sheet.



**Benefits of Schmitt-Trigger Inputs** 



## **Table of Contents**

1 Features	1	8.3 Feature Description	9
2 Applications		8.4 Device Functional Modes	
3 Description		9 Application and Implementation	11
4 Revision History	2	9.1 Application Information	
5 Pin Configuration and Functions	3	9.2 Typical Application	
Pin Functions		9.3 Application Curve	
6 Specifications	4	10 Power Supply Recommendations	14
6.1 Absolute Maximum Ratings		11 Layout	
6.2 ESD Ratings	4	11.1 Layout Guidelines	
6.3 Recommended Operating Conditions	4	11.2 Layout Example	. 14
6.4 Thermal Information	4	12 Device and Documentation Support	16
6.5 Electrical Characteristics	5	12.1 Documentation Support	16
6.6 Timing Characteristics	5	12.2 Receiving Notification of Documentation Updates	16
6.7 Switching Characteristics	6	12.3 Support Resources	16
6.8 Operating Characteristics	6	12.4 Trademarks	16
6.9 Typical Characteristics	7	12.5 Electrostatic Discharge Caution	16
7 Parameter Measurement Information		12.6 Glossary	16
8 Detailed Description	9	13 Mechanical, Packaging, and Orderable	
8.1 Overview		Information	16
8.2 Functional Block Diagram	9		

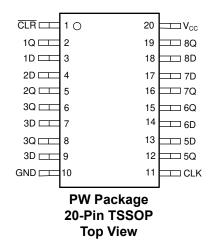
# **4 Revision History**

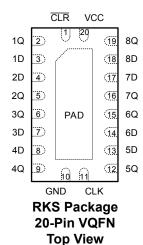
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision A (June 2021) to Revision B (October 2021)	Page
Added RKS device to Device Information Table	1
Added RKS package to pinout image and table	
Added RKS package to specification tables	
Added example layout for the RKS package	
Changes from Revision * (March 2021) to Revision A (June 2021)	Page
Changed from Application Information to Production Data	1



# **5 Pin Configuration and Functions**





## **Pin Functions**

PIN NAME NO.		I/O	DESCRIPTION		
		1/0	DESCRIPTION		
CLR	1	Input	Clear for all channels, active low		
1Q	2	Output	Output for channel 1		
1D	3	Input	Input for channel 1		
2D	4	Input	Input for channel 2		
2Q	5	Output	Output for channel 2		
3Q	6	Output	Output for channel 3		
3D	7	Input	Input for channel 3		
4D	8	Input	Input for channel 4		
4Q	9	Output	Output for channel 4		
GND	10	_	Ground		
CLK	11	Input	Clock for all channels, rising edge triggered		
5Q	12	Output	Output for channel 5		
5D	13	Input	Input for channel 5		
6D	14	Input	Input for channel 6		
6Q	15	Output	Output for channel 6		
7Q	16	Output	Output for channel 7		
7D	17	Input	Input for channel 7		
8D	18	Input	Input for channel 8		
8Q	19	Output	Output for channel 8		
V <sub>CC</sub>	20	_	Postive supply		
Thermal Pad <sup>(1)</sup> —		_	The thermal pad can be connect to GND or left floating. Do not connect to any other signal or supply.		

(1) RKS package only.



## **6 Specifications**

## **6.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		-0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	$V_{l} < 0$ or $V_{l} > V_{CC}$		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	V <sub>O</sub> = 0 to V <sub>CC</sub>		±35	mA
I <sub>CC</sub>	Continuous current through V <sub>CC</sub> or GND	·		±70	mA
TJ	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

## 6.2 ESD Ratings

			VALUE	UNIT
J. J.	Human-body model (HBM), per ANSI/ESDA/ JEDEC JS-001 <sup>(1)</sup>	±4000	V	
V <sub>(ESD)</sub>		Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>	±1500	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V <sub>CC</sub>	Supply voltage	2	6	V
VI	Input voltage	0	V <sub>CC</sub>	V
Vo	Output voltage	0	V <sub>CC</sub>	V
T <sub>A</sub>	Ambient temperature	-40	125	°C

### **6.4 Thermal Information**

		SN74F		
THERMAL METRIC <sup>(1)</sup>		RKS (VQFN)	PW (TSSOP)	UNIT
		20 PINS	20 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	83.2	134.9	°C/W
R <sub>0</sub> JC(top)	Junction-to-case (top) thermal resistance	82.6	74.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	57.4	86	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	14.5	22.5	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	56.4	85.6	°C/W
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	40.0	N/A	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

Product Folder Links: SN74HCS273

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



## **6.5 Electrical Characteristics**

over operating free-air temperature range; typical values measured at  $T_A$  = 25°C (unless otherwise noted).

	PARAMETER	TEST CC	NDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
				2 V	0.7		1.5	
V <sub>T+</sub>	Positive switching threshold			4.5 V	1.7		3.15	V
				6 V	2.1		4.2	
				2 V	0.3		1	
V <sub>T-</sub>	Negative switching threshold			4.5 V	0.9		2.2	V
				6 V	1.2		3	
				2 V	0.2		1	
$\Delta V_T$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )			4.5 V	0.4		1.4	V
				6 V	0.6		1.6	
	High-level output voltage		I <sub>OH</sub> = -20 μA	2 V to 6 V	V <sub>CC</sub> - 0.1	V <sub>CC</sub> - 0.002		
V <sub>OH</sub>		$V_I = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -6 mA	4.5 V	4	4.3		V
			I <sub>OH</sub> = -7.8 mA	6 V	5.4	5.75		
			I <sub>OL</sub> = 20 μA	2 V to 6 V		0.002	0.1	
V <sub>OL</sub>	Low-level output voltage	$V_I = V_{IH}$ or $V_{IL}$	I <sub>OL</sub> = 6 mA	4.5 V		0.18	0.3	V
			I <sub>OL</sub> = 7.8 mA	6 V		0.22	0.33	
I <sub>I</sub>	Input leakage current	V <sub>I</sub> = V <sub>CC</sub> or 0		6 V		±100	±1000	nA
I <sub>CC</sub>	Supply current	$V_I = V_{CC}$ or 0, $I_C$	<sub>D</sub> = 0	6 V		0.1	2	μA
Ci	Input capacitance			2 V to 6 V			5	pF

## **6.6 Timing Characteristics**

over operating free-air temperature range (unless otherwise noted),  $C_L$  = 50 pF

_	PARAMETER	CONDITION	V <sub>CC</sub>	MIN	MAX	UNIT
			2 V		49	
f <sub>clock</sub>	Clock Frequency		4.5 V		120	MHz
			6 V		135	
			2 V	12		
		CLR low	4.5 V	6		ns
	Dulco duration		6 V	6		
t <sub>w</sub>	Pulse duration		2 V	12		
		CLK high or low	4.5 V	6		ns
			6 V	6		
			2 V	18		
		Data before CLK↑	4.5 V	6		ns
	Cation times		6 V	6		
t <sub>su</sub>	Setup time		2 V	18		
		CLR inactive	4.5 V	6		ns
			6 V	6		
		<u>'</u>	2 V	0		
t <sub>h</sub>	Hold time, data after CLK↑		4.5 V	0		ns
			6 V	0		



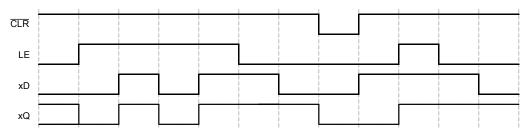


Figure 6-1. Timing Diagram

## **6.7 Switching Characteristics**

over operating free-air temperature range; typical values measured at  $T_A$  = 25°C (unless otherwise noted). See Parameter Measurement Information.  $C_L$  = 50 pF.

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
				2 V	49			
f <sub>max</sub>	Max frequency			4.5 V	120			MHz
				6 V	135			
				2 V		27.3	31.2	ns
t <sub>dis</sub>	Disable time	CLR	Any Q	4.5 V		13.3	14.8	
				6 V		11.7	13.2	
		CLK		2 V		29.1	34.6	
t <sub>pd</sub>	Propagation delay		Any Q	4.5 V		13.9	16.4	ns
				6 V		12.1	14.3	
				2 V		14.6	19.4	
t <sub>t</sub>	Transition-time		Any Q	4.5 V		7.7	9.6	ns
				6 V		7.4	10.4	

# **6.8 Operating Characteristics**

over operating free-air temperature range; typical values measured at  $T_A$  = 25°C (unless otherwise noted).

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>pd</sub>	Power dissipation capacitance per gate	No load		20		pF

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## **6.9 Typical Characteristics**

 $T_A = 25^{\circ}C$ 



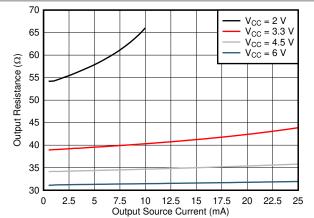
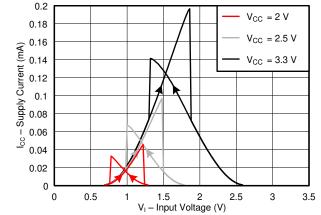


Figure 6-3. Output Driver Resistance in HIGH State



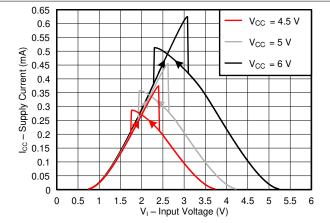


Figure 6-4. Supply Current Across Input Voltage, 2-, 2.5-, and 3.3-V Supply

Figure 6-5. Supply Current Across Input Voltage, 4.5-, 5-, and 6-V Supply

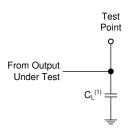


## 7 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_t$  < 2.5 ns.

For clock inputs,  $f_{max}$  is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



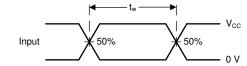


Figure 7-2. Voltage Waveforms, Pulse Duration

(1)  $C_L$  includes probe and test-fixture capacitance.

Figure 7-1. Load Circuit for Push-Pull Outputs

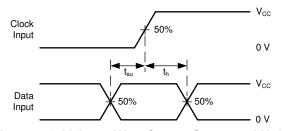
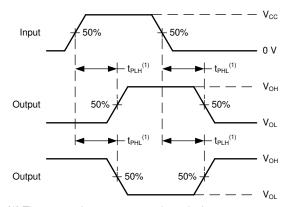
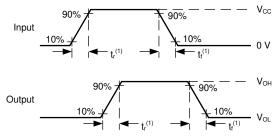


Figure 7-3. Voltage Waveforms, Setup and Hold Times



(1) The greater between  $t_{\text{PLH}}$  and  $t_{\text{PHL}}$  is the same as  $t_{\text{pd}}.$ 

Figure 7-4. Voltage Waveforms Propagation Delays



(1) The greater between  $t_{r}$  and  $t_{f}$  is the same as  $t_{t}$ .

Figure 7-5. Voltage Waveforms, Input and Output Transition Times

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## **8 Detailed Description**

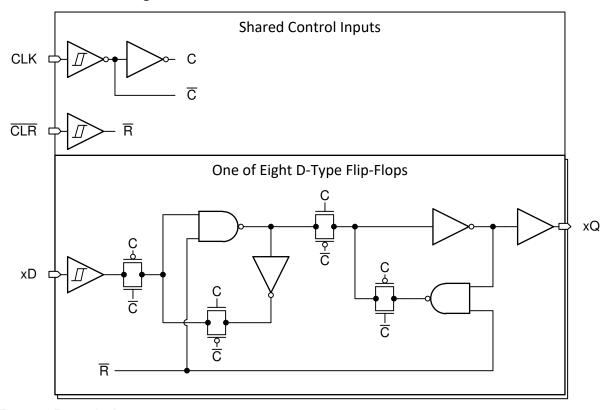
### 8.1 Overview

The SN74HCS273 contains 8 positive-edge-triggered D-type flip-flops with shared direct active low clear (CLR) input.

Information at the data (D) inputs meeting the setup time requirements is transferred to the (Q) outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not related directly to the transition time of the positive-going pulse. When CLK is at either the high or low level or transitioning from a high level to a low level, the D input has no effect at the output.

Information at the data (Q) outputs can be asychronously cleared with a low level input through the clear (CLR) pin.

## 8.2 Functional Block Diagram



## 8.3 Feature Description

## 8.3.1 Balanced CMOS Push-Pull Outputs

This device includes balanced CMOS push-pull outputs. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

Unused push-pull CMOS outputs should be left disconnected.

#### 8.3.2 CMOS Schmitt-Trigger Inputs

This device includes inputs with the Schmitt-trigger architecture. These inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics* table from the input to ground. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings* table, and the maximum input leakage current, given in the *Electrical Characteristics* table, using Ohm's law ( $R = V \div I$ ).

The Schmitt-trigger input architecture provides hysteresis as defined by  $\Delta V_T$  in the *Electrical Characteristics* table, which makes this device extremely tolerant to slow or noisy inputs. While the inputs can be driven much slower than standard CMOS inputs, it is still recommended to properly terminate unused inputs. Driving the inputs with slow transitioning signals will increase dynamic current consumption of the device. For additional information regarding Schmitt-trigger inputs, please see Understanding Schmitt Triggers.

#### 8.3.3 Clamp Diode Structure

The inputs and outputs to this device have both positive and negative clamping diodes as depicted in Electrical Placement of Clamping Diodes for Each Input and Output.

#### CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

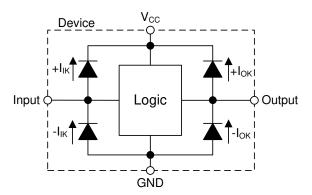


Figure 8-1. Electrical Placement of Clamping Diodes for Each Input and Output

## 8.4 Device Functional Modes

**Table 8-1. Function Table** 

	INPUTS <sup>(1)</sup>	OUTPUT <sup>(2)</sup>		
CLR	CLK	D	Q	
L	X	X	L	
Н	L, H, ↓	Х	Q <sub>0</sub>	
Н	1	L	L	
Н	1	Н	Н	

- (1) L = input low, H = input high, ↑ = input transitioning from low to high, ↓ = input transitioning from high to low, X = don't care
- (2) L = output low, H = output high,  $Q_0$  = previous state

## 9 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

## 9.1 Application Information

In this application, the SN74HCS273 is used to synchronize incoming data to the system clock on an 8-bit bus.

## 9.2 Typical Application

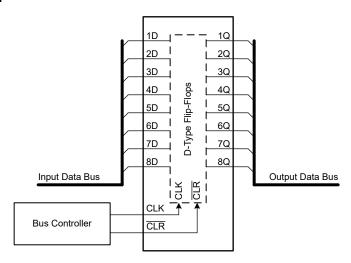


Figure 9-1. Typical Application Diagram

### 9.2.1 Design Requirements

#### 9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics*.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74HCS273 plus the maximum static supply current,  $I_{CC}$ , listed in *Electrical Characteristics* and any transient current required for switching. The logic device can only source as much current as is provided by the positive supply source. Be sure not to exceed the maximum total current through  $V_{CC}$  listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74HCS273 plus the maximum supply current, I<sub>CC</sub>, listed in *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current as can be sunk into its ground connection. Be sure not to exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.

The SN74HCS273 can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the datasheet specifications. Larger capacitive loads can be applied, however it is not recommended to exceed 50 pF.

The SN74HCS273 can drive a load with total resistance described by  $R_L \ge V_O$  /  $I_O$ , with the output voltage and current defined in the *Electrical Characteristics* table with  $V_{OH}$  and  $V_{OL}$ . When outputting in the high state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the  $V_{CC}$  pin.



Total power consumption can be calculated using the information provided in CMOS Power Consumption and Cpd Calculation.

Thermal increase can be calculated using the information provided in Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices.

#### **CAUTION**

The maximum junction temperature,  $T_{J(max)}$  listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

#### 9.2.1.2 Input Considerations

Input signals must cross  $V_{t-(min)}$  to be considered a logic LOW, and  $V_{t+(max)}$  to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either  $V_{CC}$  or ground. These can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input is to be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The resistor size is limited by drive current of the controller, leakage current into the SN74HCS273, as specified in the *Electrical Characteristics*, and the desired input transition rate. A 10-k $\Omega$  resistor value is often used due to these factors.

The SN74HCS273 has no input signal transition rate requirements because it has Schmitt-trigger inputs.

Another benefit to having Schmitt-trigger inputs is the ability to reject noise. Noise with a large enough amplitude can still cause issues. To know how much noise is too much, please refer to the  $\Delta V_{T(min)}$  in the *Electrical Characteristics*. This hysteresis value will provide the peak-to-peak limit.

Unlike what happens with standard CMOS inputs, Schmitt-trigger inputs can be held at any valid value without causing huge increases in power consumption. The typical additional current caused by holding an input at a value other than V<sub>CC</sub> or ground is plotted in the *Typical Characteristics*.

Refer to the Feature Description section for additional information regarding the inputs for this device.

## 9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V<sub>CC</sub> or ground.

Refer to Feature Description section for additional information regarding the outputs for this device.

#### 9.2.2 Detailed Design Procedure

- Add a decoupling capacitor from V<sub>CC</sub> to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V<sub>CC</sub> and GND pins. An example layout is shown in the *Layout* section.
- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit, however it will ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the SN74HCS273 to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than  $(V_{CC} / I_{O(max)}) \Omega$ . This will ensure that the maximum output current from the *Absolute Maximum Ratings* is not violated. Most CMOS inputs have a resistive load measured in megaohms; much larger than the minimum calculated above.
- 4. Thermal issues are rarely a concern for logic gates, however the power consumption and thermal increase can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation.

## 9.3 Application Curve

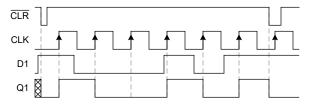


Figure 9-2. Application Timing Diagram, One Data Channel Shown

## 10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in given example layout image.

## 11 Layout

## 11.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V<sub>CC</sub>, whichever makes more sense for the logic function or is more convenient.

### 11.2 Layout Example

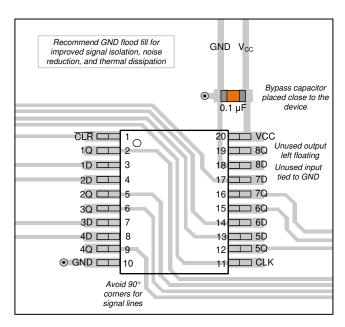


Figure 11-1. Example Layout for the SN74HCS273 PW package

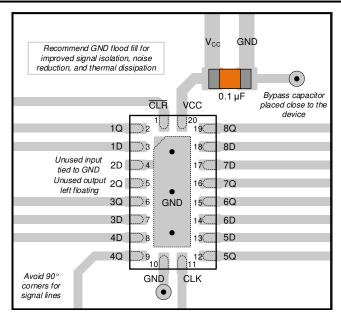


Figure 11-2. Example Layout for the SN74HCS273 RKS package



## 12 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

### **12.1 Documentation Support**

#### 12.1.1 Related Documentation

For related documentation see the following:

- Texas Instruments, HCMOS Design Considerations application report
- Texas Instruments, CMOS Power Consumption and Cpd Calculation application report
- · Texas Instruments, Designing With Logic application report

## 12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

## 12.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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#### 12.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

## 12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 12.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74HCS273PWR	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS273	Samples
SN74HCS273RKSR	ACTIVE	VQFN	RKS	20	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS273	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

www.ti.com 23-Oct-2021

#### OTHER QUALIFIED VERSIONS OF SN74HCS273:

Automotive: SN74HCS273-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

# PACKAGE MATERIALS INFORMATION

www.ti.com 24-Oct-2021

## TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HCS273PWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74HCS273RKSR	VQFN	RKS	20	3000	180.0	12.4	2.8	4.8	1.2	4.0	12.0	Q1

www.ti.com 24-Oct-2021



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HCS273PWR	TSSOP	PW	20	2000	853.0	449.0	35.0
SN74HCS273RKSR	VQFN	RKS	20	3000	210.0	185.0	35.0

2.5 x 4.5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





PLASTIC QUAD FLATPACK - NO LEAD



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If some or all are implemented, recommended via locations are shown.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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